

Title (en)

EPOXY RESIN COMPOSITION AND SEMICONDUCTOR DEVICE

Title (de)

EPOXIDHARZZUSAMMENSETZUNG UND HALBLEITERANORDNUNG

Title (fr)

COMPOSITION A BASE DE RESINE EPOXY ET DISPOSITIF SEMI-CONDUCTEUR

Publication

**EP 1137708 A1 20011004 (EN)**

Application

**EP 00956907 A 20000904**

Priority

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Abstract (en)

[origin: WO0118115A1] The present invention provides an epoxy resin composition for encapsulating of semiconductors which is suitable for area mounting type semiconductor devices and is less in warping and excellent in soldering crack resistance. The epoxy resin composition comprises (A) an epoxy resin, (B) a phenolic resin, (C) a curing accelerator and (D) an inorganic filler as main components, where properties of a cured product formed by heating and curing the epoxy resin composition satisfy expressions,  $a>/=10<R>$  ( $R=10x(b+c)-1$ ),  $300</=a</=20000$  and  $0.15</=b+c</=0.50$  in which a denotes a flexural modulus (N/mm $<2>$ ) at molding temperature, b denotes a cure shrinkage (%) and c denotes a heat shrinkage (%) of from molding temperature to room temperature.

IPC 1-7

**C08L 63/00; H01L 23/29; C08L 61/04; C08L 65/00**

IPC 8 full level

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CPC (source: EP KR)

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